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Substitute for form 1449A/PTO (modified) INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Complete if known	
				Application Number	Not yet assigned
				Filing Date	Concurrently Herewith
				First Named Inventor	Horst Haussecker
				Group Art Unit	Not yet assigned
				Examiner Name	Not yet assigned
Sheet	1	of	3	Attorney Docket	42P14242X

U.S. PATENT DOCUMENTS						
Examiner Initials	Cite No. ¹	U.S. Patent Document Number	Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines Where Relevant Passages or Figures Appear
BL		5,472,881		Beebe, et al.	12/05/1995	
		5,497,656		Kado, et al.	03/12/1996	
		6,044,221		Gupta, et al.	03/28/2000	
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		6,280,939		Allen	08/28/2001	
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V		6,360,020		Panis	03/19/2002	

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
BL		United States Patent Application Publication, Publication No. US 2001/0052257, Magerle, Publication Date December 20, 2001.	

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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard St.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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B L		ANDO, et al., "A High-Speed Atomic Force Microscope for Studying Biological Macromolecules," <i>PNAS</i> , Vol. 98, No. 22, pp. 12468-12472, October 2001.	
		CLAUSS, et al., "Atomic Resolution STM Imaging of a Twisted Single-Wall Carbon Nanotube," <i>Physical Review B</i> , Volume 58, Number 8, pp. 4266-4269, August 1998.	
		CLAUSS, et al., "Electron Backscattering on Single-Wall Carbon Nanotubes Observed by Scanning Tunneling Microscopy," <i>Europhys. Lett.</i> , 47(5), pp. 601-607, 1999.	
		FREITAG, et al., "Local Electronic Properties of Single-Wall Nanotube Circuits Measured by Conducting-Tip AFM," <i>Physical Review B</i> , Volume 62, Number 4, pp. 2307-2310, July 2000.	
		FRISBIE, et al., "Functional Group Imaging by Chemical Force Microscopy," <i>Science</i> , Vol. 265, pp. 2071-2074, September 1994.	
		HANSMA, et al., Atomic Force Microscopy of DNA in Aqueous Solutions," <i>Nucleic Acids Res.</i> , 21:505-512, 1993.	
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		KIM, et al., "AFM Study of Surface Phenomena Based on C ₆₀ Film Growth," <i>Applied Surface Science</i> , 130-132, pp.602-609, 1998.	
B L		KLEIN, et al., "Ordered Stretching of Single Molecules of Deoxyribose Nucleic Acid Between Microfabricated Polystyrene Lines," <i>Applied Physics Letters</i> , Vol. 78, Number 16, pp. 2396-2398, April 2001.	

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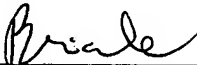
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BL		KOBAYASHI, et al., "Imaging of Fullerene Molecules on Si(111)-7 7 Surface with NC-AFM," <i>Applied Surface Science</i> , 157, pp. 228-232, 2000.	
		MÖLLER, et al., "Tapping-Mode Atomic Force Microscopy Produces Faithful High-Resolution Images of Protein Surfaces," <i>Biophys. J.</i> , 77:1150-8, 1999.	
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		NICEWARMER-PENA, "Submicrometer Metallic Barcodes," <i>Science</i> , Vol. 294, pp. 137-141, October 2001.	
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